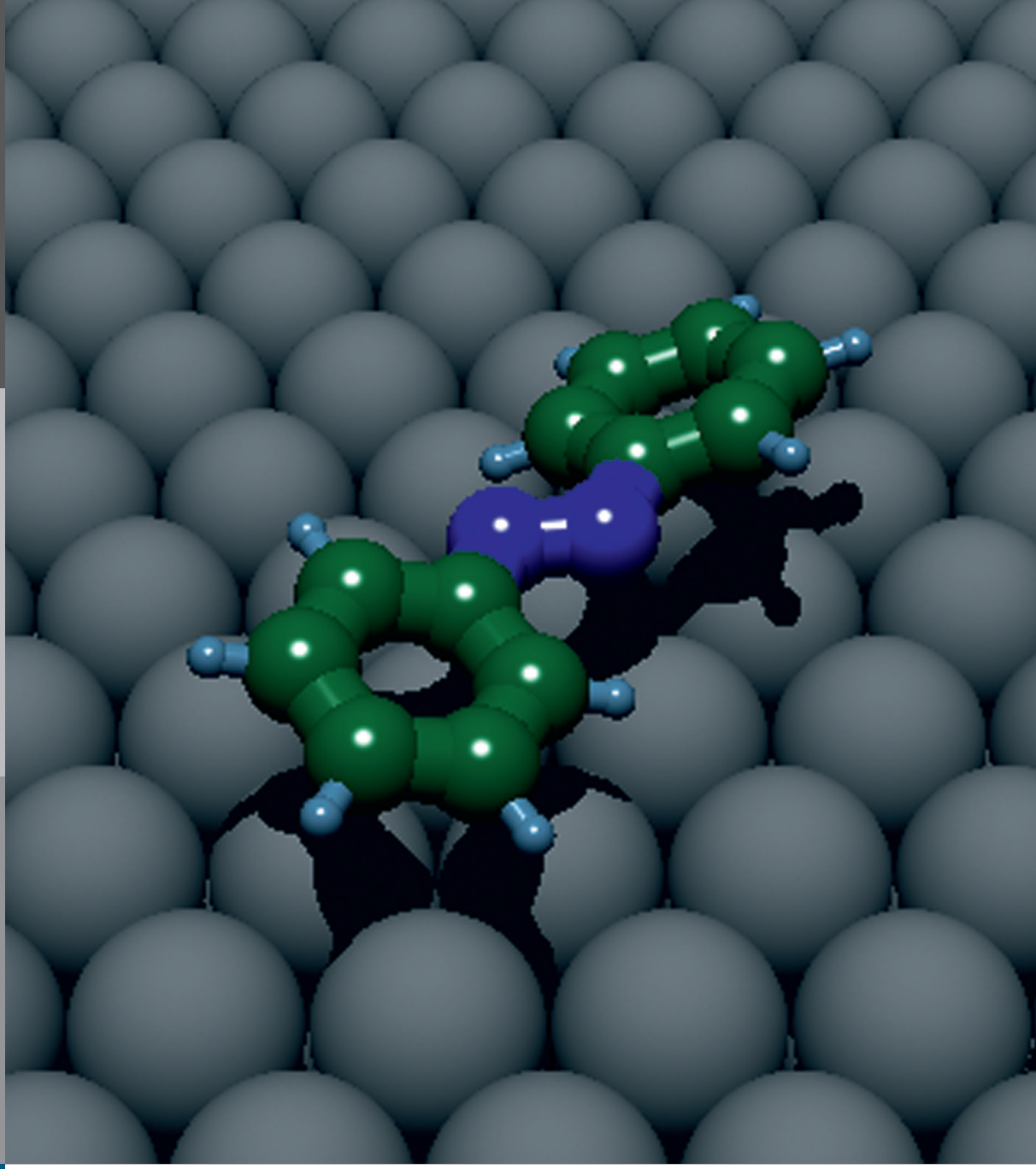

Study of Molecule-Metal Interfaces by Means of the Normal Incidence X-ray Standing Wave Technique

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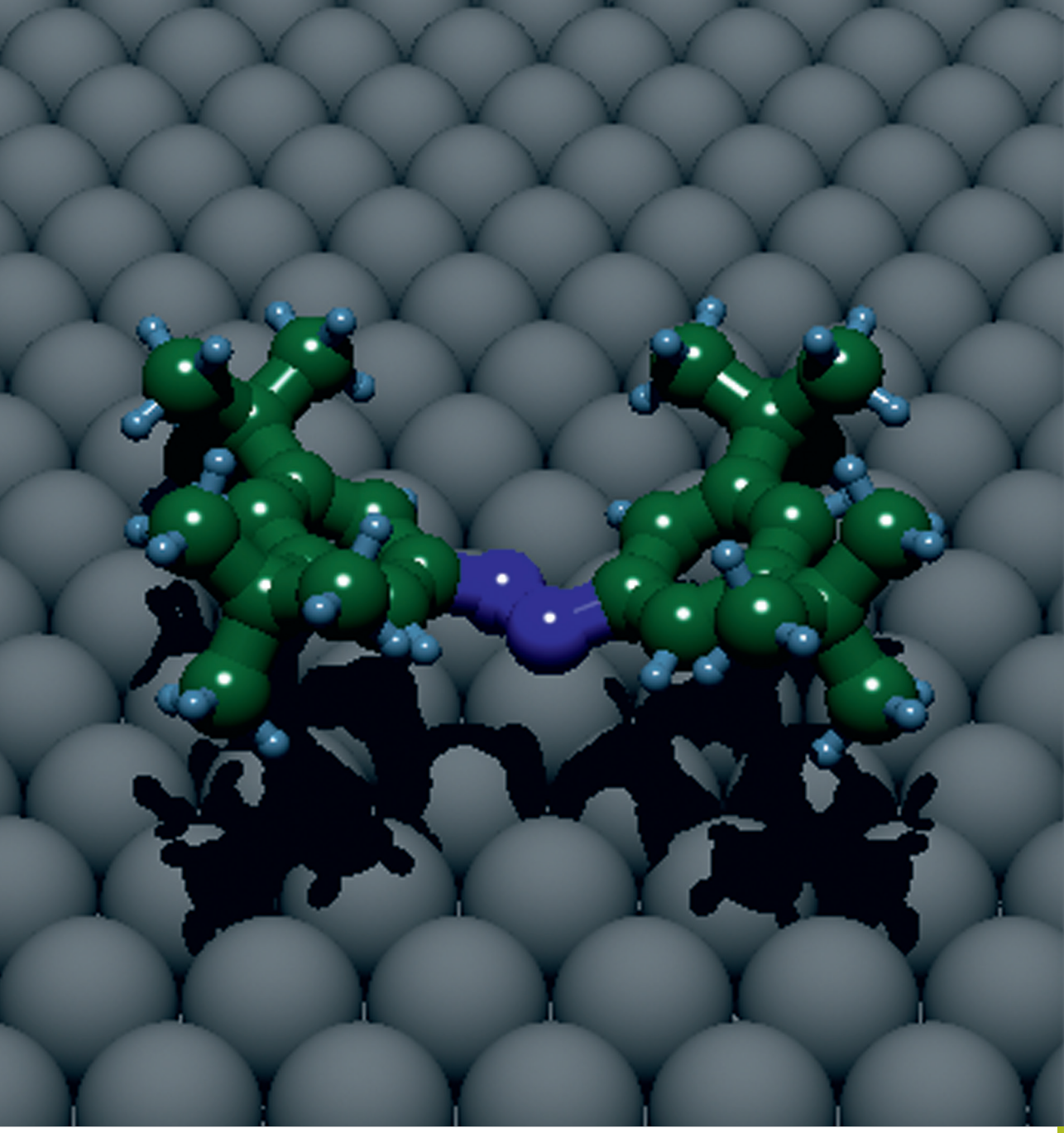

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